

**DESCRIPTION**

The AM05N06 is available in SOT-223 Package

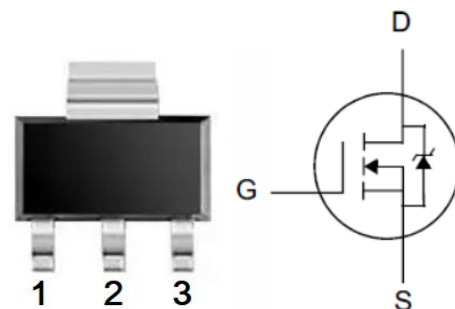
BVDSS	RDS(ON)	ID
60V	66mΩ	5A

ORDERING INFORMATION

Package Type	Part Number	
SOT-223	N3	AM05N06N3R
SPQ: 2,500pcs/Reel		AM05N06N3VR
Note	V: Halogen free Package R: Tape & Reel	
AiT provides all RoHS products		

FEATURE

- Advanced high cell density Trench Technology
- $R_{DS(ON)typ.}=66m\Omega @ V_{GS}=10V$
- Excellent dv/dt effect decline
- Super Low Gate Charge

PIN DESCRIPTION

SOT-223

Pin#	Symbol	Function
1	G	Gate
2	D	Drain
3	S	Source

ABSOLUTE MAXIMUM RATINGS

$T_A = 25^{\circ}C$, unless otherwise specified.

V_{DS} , Drain-Source Voltage		60V
V_{GS} , Gate-Source Voltage		$\pm 20V$
I_D , Continuous Drain Current, $V_{GS}@10V^{(1)}$	$T_A = 25^{\circ}C$	5.0A
	$T_A = 70^{\circ}C$	1.8A
I_{DM} , Pulsed Drain Current $^{(2)}$		9.2A
P_D , Total Power Dissipation $^{(3)}$	$T_A = 25^{\circ}C$	1W
T_J , Operating Junction Temperature Range		$-55^{\circ}C \sim +150^{\circ}C$
T_{STG} , Storage Temperature Range		$-55^{\circ}C \sim +150^{\circ}C$
$R_{\theta JA}$, Thermal Resistance Junction-Ambient $^{(1)}$		125°C/W
$R_{\theta JC}$, Thermal Resistance Junction-Case $^{(1)}$		80°C/W

Stresses above may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated in the Electrical Characteristics are not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

(1) The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.

(2) The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$

(3) The power dissipation is limited by 150°C junction temperature.



ELECTRICAL CHARACTERISTICS

T_J = 25°C, unless otherwise specified.

Parameter	Symbol	Conditions	Min	Typ.	Max	Unit
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	60	-	-	V
BV _{DSS} Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_J$	I _D =1mA Reference 25°C	-	0.054	-	V/°C
Static Drain-Source On-Resistance ⁽²⁾	R _{DS(ON)}	V _{GS} =10V, I _D =2A	-	66	105	mΩ
		V _{GS} =4.5V, I _D =1A	-	85	110	
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} = V _{GS} , I _D =250μA	1.2	-	2.5	V
V _{GS(TH)} Temperature Coefficient	$\Delta V_{GS(TH)}$		-	-4.96	-	mV/°C
Drain-Source Leakage Current	I _{DSS}	V _{DS} =48V, V _{GS} =0V, T _J =25°C	-	-	1	μA
		V _{DS} =48V, V _{GS} =0V, T _J =55°C	-	-	5	
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V,	-	-	±100	nA
Forward Transconductance	g _{fs}	V _{DS} =5V, I _D =2A	-	13	-	S
Total Gate Charge (4.5V)	Q _g	V _{DS} =48V, V _{GS} =4.5V, I _D =2A	-	5.0	7.0	nC
Gate-Source Charge	Q _{gs}		-	1.68	2.4	
Gate-Drain Charge	Q _{gd}		-	1.9	2.7	
Turn-on Delay Time	t _{d (ON)}	I _D =2A, V _{DD} =30V, V _{GS} =10V, R _G =3.3Ω	-	1.6	3.2	ns
Rise Time	t _r		-	7.2	13	
Turn-Off Delay Time	t _{d (OFF)}		-	25	50	
Fall Time	t _f		-	14.4	28.8	
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =15V, f=1.0MHz	-	511	715	pF
Output Capacitance	C _{oss}		-	38	53	
Reverse Transfer Capacitance	C _{rss}		-	25	35	
Diode Characteristics						
Continuous Source Current ⁽¹⁾⁽³⁾	I _S	V _G =V _D =0V, Force Current	-	-	2.3	A
Maximum Pulsed Current ⁽²⁾⁽³⁾	I _{SM}		-	-	9.2	A
Diode Forward Voltage ⁽²⁾	V _{SD}	V _{GS} =0V , I _S =1A , T _J =25 °C	-	-	1.2	V
Reverse Recovery Time	T _{rr}	I _F =2A , dI/dt=100A/μs , T _J =25°C	-	9.7	-	ns
Reverse Recovery Charge	Q _{rr}		-	5.8	-	nC

(1) The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.

(2) The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%

(3) The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation



TYPICAL PERFORMANCE CHARACTERISTICS

Fig 1. Typical Output Characteristics

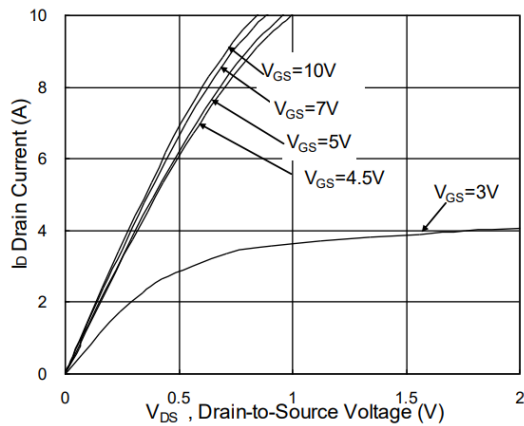


Fig 2. On-Resistance vs. Gate-Source

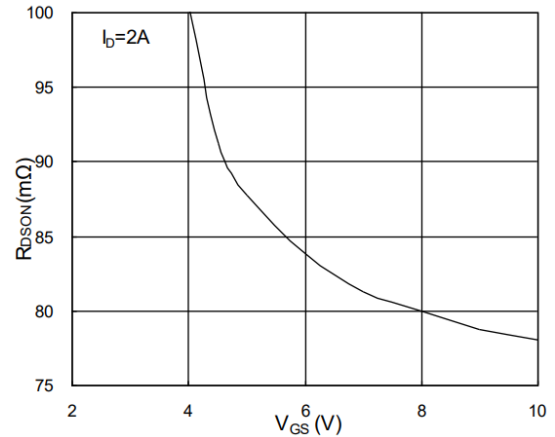


Fig 3. Forward Characteristics of Reverse

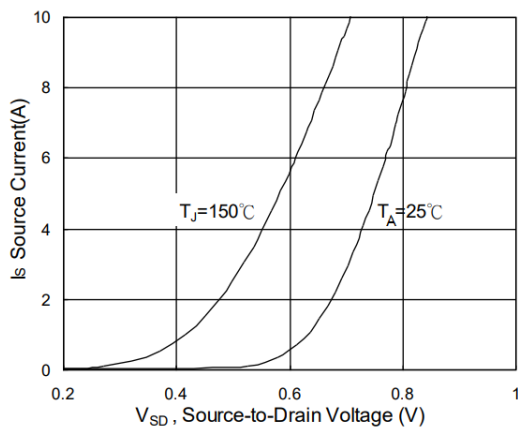


Fig 4. Gate-Charge Characteristics

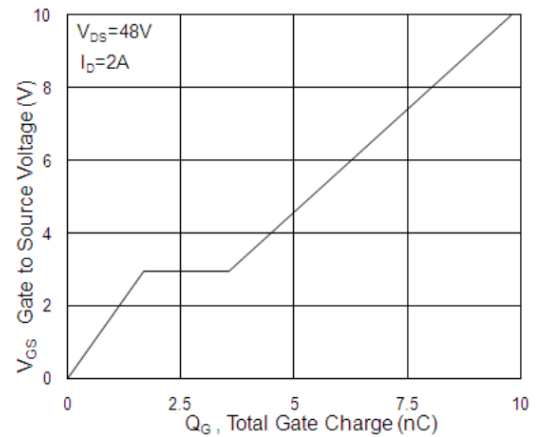


Fig 5. Normalized $V_{GS(TH)}$ vs. T_J

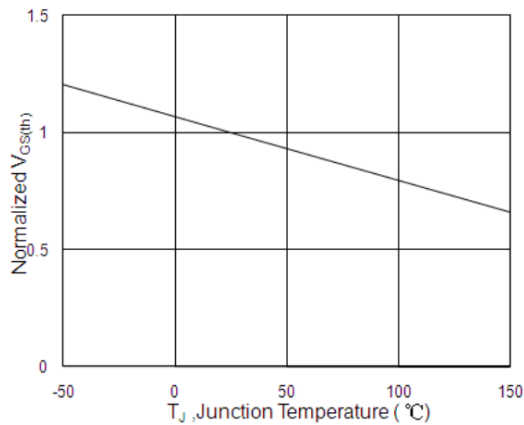


Fig 6. Normalized $R_{DS(on)}$ vs. T_J

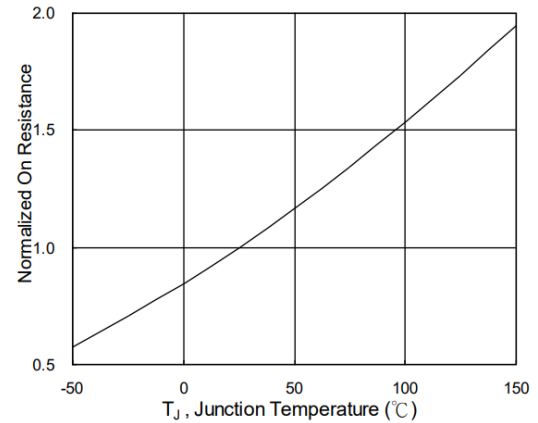




Fig 7. Capacitance

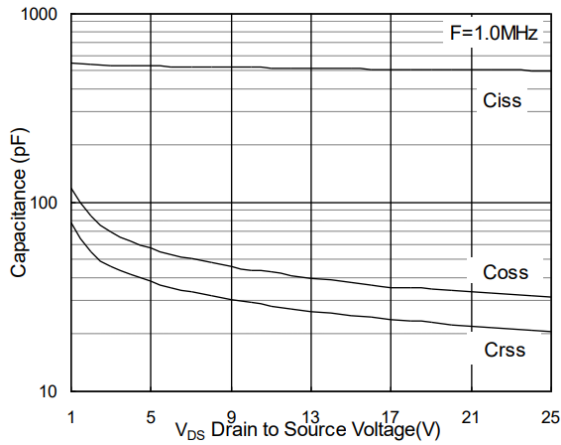


Fig 8. Safe Operating Area

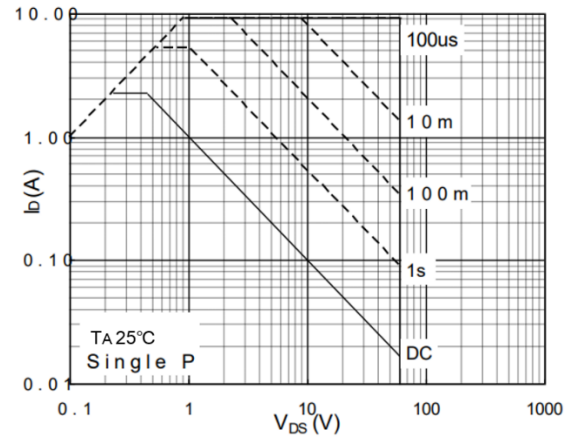


Fig 9. Normalized Maximum Transient Thermal Impedance

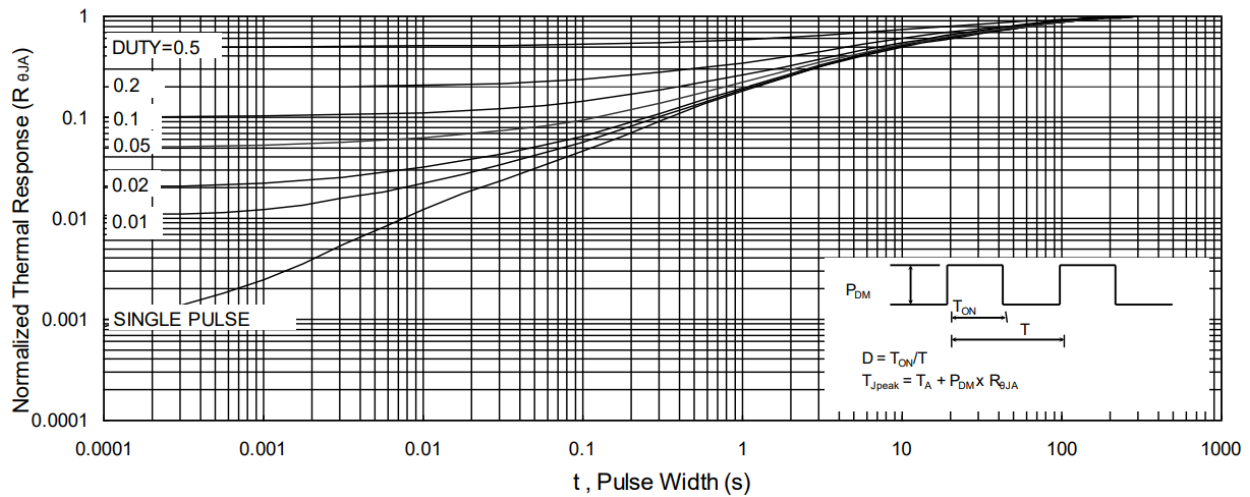


Fig 10. Switching Time Waveform

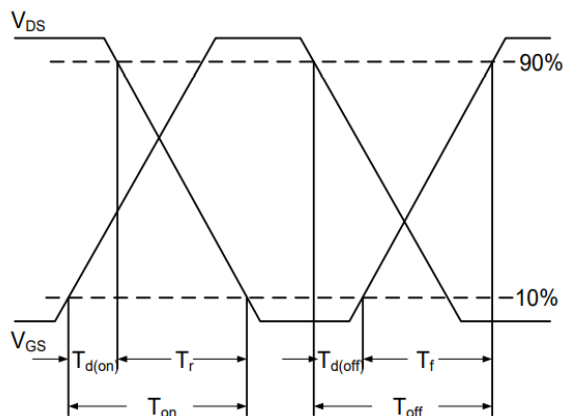
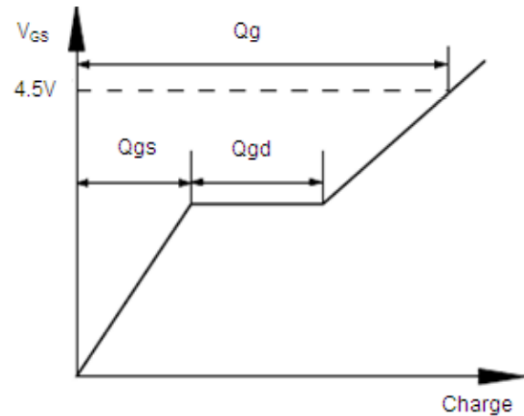


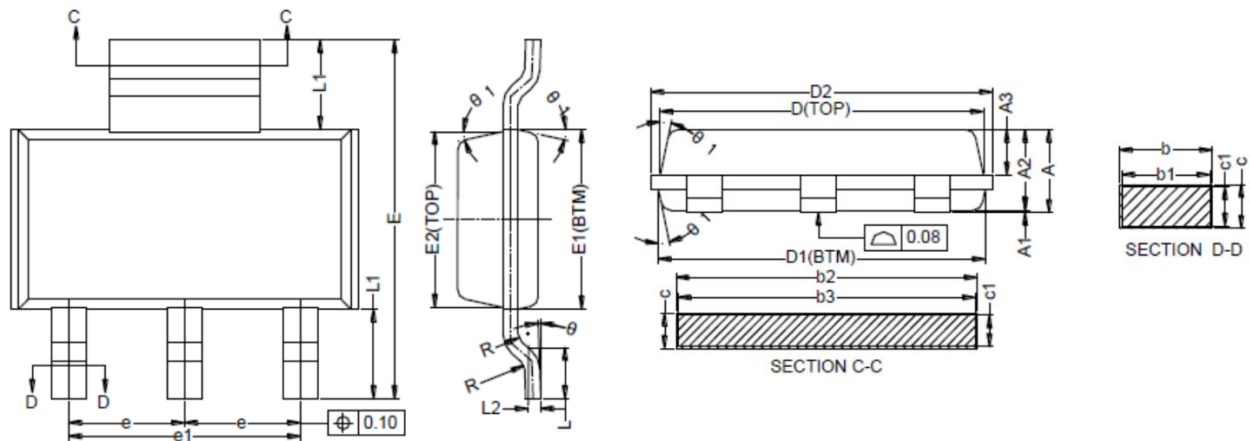
Fig 11. Gate Charge Waveform





PACKAGE INFORMATION

Dimension in SOT-223 (Unit: mm)



Symbol	Min.	Max.
A	-	1.80
A1	0.02	0.10
A2	1.50	1.70
A3	0.80	1.00
b	0.67	0.80
b1	0.66	0.76
b2	2.96	3.09
b3	2.95	3.05
c	0.30	0.35
c1	0.29	0.31
D	6.48	6.58
D1	6.55	6.65
D2	-	7.05
E	6.80	7.20
E1	3.40	3.60
E2	3.33	3.53
e	2.30(BSC)	
e1	4.60(BSC)	
L	0.80	1.20
L1	1.750(REF)	
L2	0.250(BSC)	
R	0.10	-
R1	0.10	-
θ	0°	8°
θ1	10°	14°



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